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	A Sign S		Page <u>1</u> of <u>2</u>
Form PTO-1449 U.S. DEPARTMENT OF COMMERCIAN BY PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE		Atty. Docket No. 98095DIV3	Serial No. 10/008,653
STATEMENT BY APPLICA			
.(Use several sheets if necessary)			
		Applicant Gonzalez et al.	
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